

# THE INTEGRATED CIRCUITS PHOTOMASKS IMAGES ALIGNEMENT FOR AUTOMATED OPTICAL INSPECTION SYSTEM

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**Abstract:** *The automated optical inspection system for integrated circuits photo masks is designed. This low error probability system based on application of hyperbolic wavelet transforms and integrated circuits photo masks fiducial marks geometric moment features. The experimental results proved the high noise stability properties, which allow reducing lighting apparatus and high precision mechanism conditions.*

**Key words:** *automated optical inspection system, hyperbolic wavelet transforms, integrated circuits, photo masks, alignment*



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